EE493 ENGINEERING DESIGN-1

Test and Measurement Techniques



Outline

- Test and Measurement
- Measurement
 - What is Measurement?
 - Measurement Reliability
- Test Plan
 - Test Plan Examples
- Some tests recommended for EE493-EE494



Test and Measurement

- Measurement: The act of measuring something
 - Current
 - Voltage
 - Speed
 - Weight

- Test: A procedure intended to establish
 - Quality
 - Performance
 - Reliability

Test can be a combination of various measurements.



Measurement

- Measurement is
 - <u>Systematic</u>
 - <u>Replicable</u>

by which objects or events are quantified.

- <u>Usually</u> achieved by the assignment of <u>numerical</u> values.
 - International System of Units (SI)
- Measurement is more than reporting whether something is simply
 - Working or
 - Not working



International System of Units (SI)

Base Units

| Quantity | SI unit | Symbol | |
|---------------------|--------------------------|---------|--|
| Length | meter | m | |
| Mass | kilogram | kg | |
| Time | second | S | |
| Electric current | ampere | А | |
| Temperature | kelvin or degree Celsius | K or °C | |
| Luminous intensity | candela | cd | |
| Amount of substance | mole | mol | |



International System of Units (SI)-2

Derived Unit Examples

| Quantity | SI unit | Symbol |
|--------------|-----------------------------|--------------------------------------|
| Area | square meter n | |
| Volume | cubic meter | m ³ |
| Speed | meter per second | ms ⁻¹ or m/s |
| Acceleration | meter per second per second | ms ⁻² or m/s ² |
| Force | newton | Ν |
| Energy | joule | J |
| Power | watt W | |

What about Volt?

Voltage is W/A or J/C which equals to kg.m².s⁻³.A⁻¹



Prefixes Used for Multiples of Units

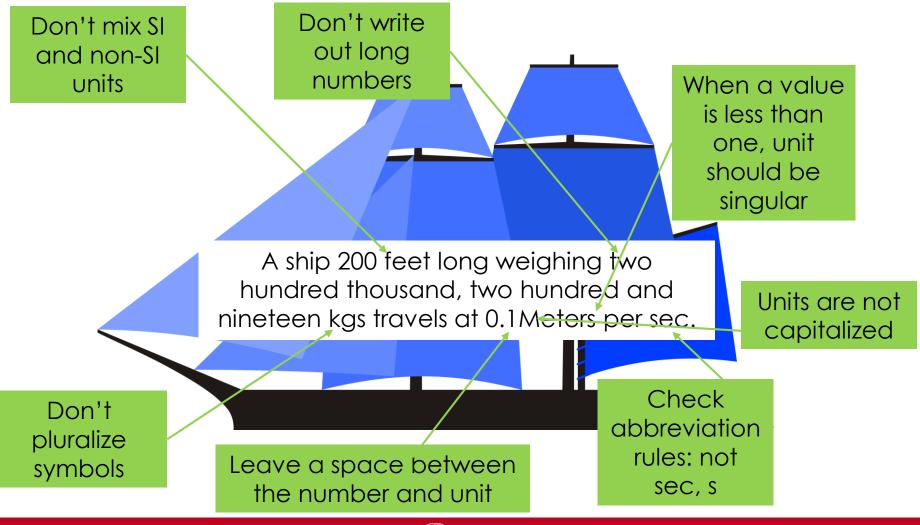
| Prefix | Symbol | Power of 10 | |
|--------|--------|------------------|--|
| yotta | Y | 1024 | |
| zetta | Z | 1021 | |
| exa | E | 10 ¹⁸ | |
| peta | Р | 10 ¹⁵ | |
| tera | Т | 1012 | |
| giga | G | 109 | |
| mega | М | 106 | |
| kilo | k | 10 ³ | |
| deci | d | 10-1 | |
| centi | С | 10-2 | |
| Milli | m | 10-3 | |
| micro | μ | 10-6 | |
| nano | n | 10-9 | |
| pico | р | 10-12 | |
| femto | f | 10-15 | |
| atto | a | 10-18 | |
| zepto | Z | 10-21 | |
| yocto | У | 10-24 | |

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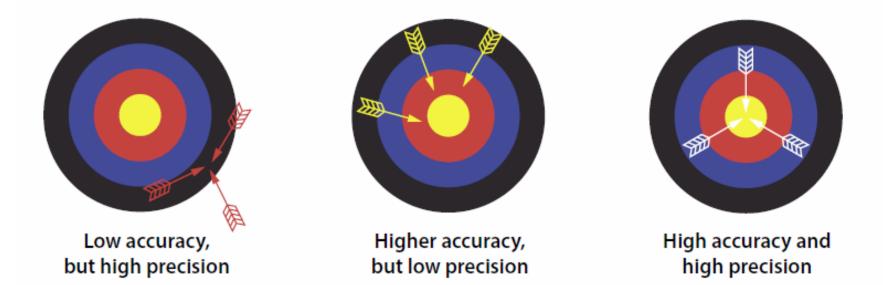


Expressing Measurement Results

In the example below the most important rules are broken!



Quality of the Measurement



- In order to get high accuracy and precision,
- You need to have your measurement system calibrated
- You need to calculate (and possibly reduce) your error margin



Measurement Reliability

- Measurement yields consistent scores over <u>repeated</u> measurements.
- Three criteria for reliability
- Test-Retest Reliability

Measure the same item, do you get the same result?

You need to repeat measurement and take average

Inter-item Reliability

Measure a different item, using the same setup, do you get the same result? This will show you the process variation

• Inter-observer Reliability

Let someone to measure it for you, do you get the same result? You need to have a <u>test-plan.</u>



Test-Retest Reliability

- Variation in test-retest can be due to
 - Noise
 - Unreliable measurement technique or setup
 - Change in the environment or conditions
 - Faulty parts



Inter-item Reliability

- Variation can be due to
 - Part to part variation
 - Check the data-sheet to confirm
 - Testing method and testing system problems



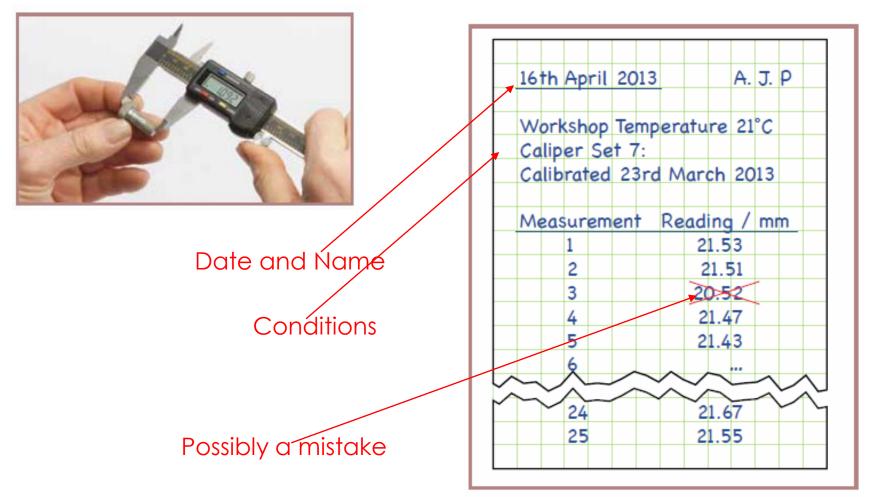
Inter-Observer Reliability

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Uncertainty Analysis-1

• Measuring the length of an object with an electronic callipers



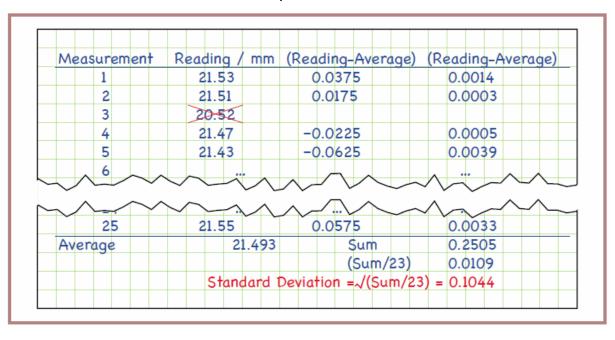


Uncertainty Analysis-2

- Take the average of all measurements (21.53+21.51+21.47+21.43+...)/24=21.493 mm
- Calculate standard deviation as

standard deviation =

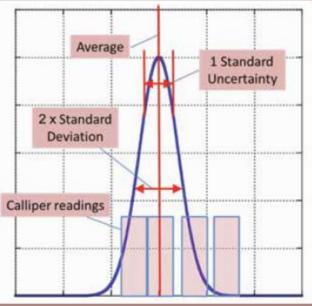
$$\frac{\sum_{i=1}^{n} (reading_i - average)^2}{n-1}$$





Uncertainty Analysis-3

- If you take 100 more measurements you will improve your confidence level.
- For n readings standard uncertainty is given as standard uncertainty = $\frac{standard \ deviation}{\sqrt{n}}$
- For 24 measurements the standard uncertainty would be 0.021 mm.



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Test Plan

- Strategy document to verify a system meets its specifications
 - Must test the limits
 - Not used to verify your design in your design comfort zone
- Must Include
 - Detailed test methodology
 - Number of samples to be tested
 - The variation to be applied (e.g., temperature, supply voltage)
 - Expected results



Test Plan Example

Test Description: Switching Time: Test#4

| | | | # Samples | 5 |
|----------------|--|------|-----------------|---------|
| Test Type | Test Conditions | Room | + 85 ° C | -45 ° C |
| Switching Time | Vdd = 5.0 V | 5 | 3 | 3 |
| | Use Tune-1 board Measure from RFIN to RFOUT Measure from minimum atten to Maximum attenuation case in parallel mode. Switching period 100uS Duty cycle 50% RF input power TBD | | | |

Test Setup(s)

(TTL level, Vlow=0.8V, Vhigh=2V). Measure from 50% control to 90% RF.(Trise) Measure from 50% control to 10% RF (Tfall) Calibration Method: Standard

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Test Plan Examples 'ctnd

Test Results

Store in separate sub-directories by Serial No./Temp/Voltage. Make sure file names are consistent from directory to directory.

Expected Results

Rise Time and Fall Time is expected around 1uS.

| Due Date | |
|----------|--|
| Approved | |
| Priority | |



Some Tests Recommended for EE493-EE494

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Some Common Subsystems

- Object Detection Subsystem
 - Ex: Image processing, sensors, micro-computer, etc.
- Movement Subsystem
 - Motors, motor drivers, wheels, chassis, microcontrollers, etc.
- Holding and Dropping Subsystem
 - Motors, motors drivers, wheels, arms, microcontrollers, etc.
- Power Supply
 - Battery, power controllers, low power indicators, etc.



Important Remarks

- All of the components must be tested separately and they must be combined for overall testing.
- Measure of success must be defined
 - Ex: The object detection subsystem must not be affected by lighting conditions.
- Test results must be provided to verify the measurable objectives.
- Number of trials and statistical properties such as mean and stdev. must be given.



Example: Distance Sensor

- Any applicable test to provide the following:
 - Plots, tabulated data or measurement results showing measured distance (cm) vs real distance (cm) with error values in percentage.

Example: Our sensor measures the distance of objects that are about 30 cm away. It has a 50% detection error over 30 cm distance. Under controlled lighting conditions (florescent light with uniform lighting) our result has 60% accuracy over the same distance. These data are collected over 5 repeated measurements with direct line of sight.

This claim should be supported by measurement results on a plot or in a table.



Example: Motor, Motor Driver, and Controller

- For the operating voltage range, the current ratings must be measured; durability tests must be performed by applying high voltage in the operation range for enough time.
- In order to observe the accuracy of the movement of the robot, speed, deviation, and rotation tests must be applied.
- Hardware PWM outputs of the microcontroller with different duty cycles at different frequencies must be provided.



Example: Movement Subsystem

The robot must be checked whether it can travel without a • significant deviation through a linear path.



Test Results for the Final Product

The number of trials and the success rate must be provided. •

